

Scattering (continued)

Note Title

30/01/2012

$$\frac{1}{N} \text{ or } \frac{1}{V} \quad \frac{d^2\sigma}{d\Omega} \propto |U(\vec{q})|^2 S(\vec{q})$$

depends on probing particle

$$S(\vec{q}) = \left(\frac{1}{N} \right) \left\langle \sum_{\alpha, \alpha'} e^{i\vec{q} \cdot (\vec{r}_{\alpha} - \vec{r}_{\alpha'})} \right\rangle : \text{Structure factor}$$

: F.T. of correlation fn. $C_{nn}(\vec{r}_1, \vec{r}_2) = \langle n(\vec{r}_1) n(\vec{r}_2) \rangle$

$$S(\vec{q}) = \frac{1}{V} \int e^{-i\vec{q} \cdot (\vec{r}_1 - \vec{r}_2)} C_{nn}(\vec{r}_1, \vec{r}_2) d\vec{r}_1 d\vec{r}_2 \quad \checkmark$$

Urseil function.

$$\begin{aligned} S_{nn}(\vec{r}_1, \vec{r}_2) &\equiv \langle \delta n(\vec{r}_1) \delta n(\vec{r}_2) \rangle \\ &= \langle (n(\vec{r}_1) - \langle n(\vec{r}_1) \rangle) (n(\vec{r}_2) - \langle n(\vec{r}_2) \rangle) \rangle \\ &= \langle n(\vec{r}_1) n(\vec{r}_2) \rangle - \langle n(\vec{r}) \rangle^2 \\ &= \underbrace{C_{nn}(\vec{r}_1, \vec{r}_2) - \langle n(\vec{r}) \rangle^2}_{\text{Useful b/c}} \quad \checkmark \end{aligned}$$

Useful b/c $S_{nn} \rightarrow 0$ as $|\vec{r}_1 - \vec{r}_2| \rightarrow \infty$

$$S_{nn}(\vec{q}) = \frac{1}{V} \int d\vec{r}_1 d\vec{r}_2 e^{-i\vec{q} \cdot (\vec{r}_1 - \vec{r}_2)} S_{nn}(\vec{r}_1, \vec{r}_2) \quad \checkmark$$

$$S(\vec{q}) = S_{nn}(\vec{q}) + \frac{1}{V} \left| \int d\vec{r} e^{-i\vec{q} \cdot \vec{r}} \langle n(\vec{r}) \rangle \right|^2$$

For liquid: $\langle n(\vec{x}) \rangle = \langle n \rangle$ constant

$$S(\vec{q}) = \underbrace{S_{nn}(\vec{q})}_{\text{scattering}} + \langle n \rangle^2 (2\pi)^3 \delta(\vec{q})$$

For solid: (crystal). $\langle n(\vec{x}) \rangle$ is a periodic fn of \vec{x}

$$\langle n(\vec{x}) \rangle = \sum_{\vec{G}} \langle n_{\vec{G}} \rangle e^{i\vec{G} \cdot \vec{x}} \quad ; \text{ Fourier expansion}$$

Fourier transform of $\langle n(\vec{x}) \rangle$ is not zero

@ only \vec{G} (reciprocal lattice vector)

$$S(\vec{q}) = S_{nn}(\vec{q}) + \sum_{\vec{G}} |\langle n_{\vec{G}} \rangle|^2 (2\pi)^3 \delta(\vec{q} - \vec{G})$$

static disorder \leftarrow fluctuation diffuse scattering \rightarrow elastic (diffraction) part \rightarrow Bragg peaks

Analogously consider time

If we define time-dep. Ursell fn. as

$$S_{nn}(\vec{x}_1, \vec{x}_2, t, t') = \langle \delta n(\vec{x}_1, t) \delta n(\vec{x}_2, t') \rangle$$

Dynamic Structure factor becomes

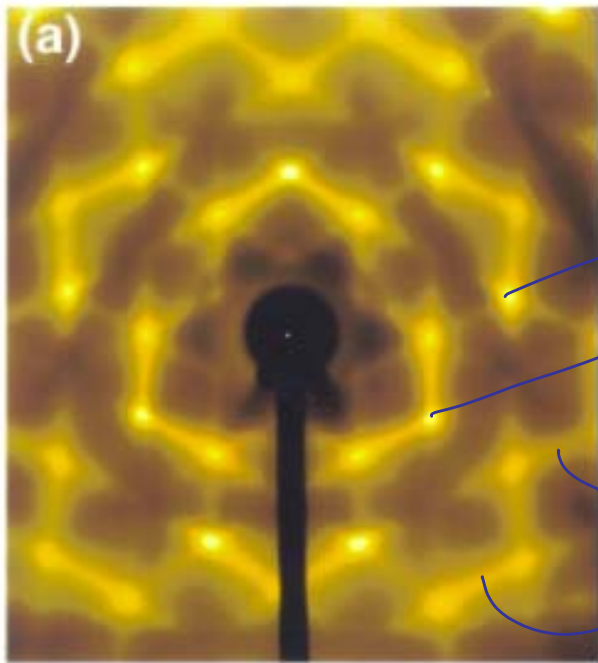
$$\Rightarrow S(\vec{q}, \omega) = S_{nn}(\vec{q}, \omega) + \sum |\langle n_{\vec{G}} \rangle|^2 (2\pi)^3 \delta(\vec{q} - \vec{G}) \delta(\omega)$$

time-dep.
fluctuations

Static (time-indep.) order
 \Rightarrow usual diffraction

(quantum/thermal
fluctuations)

Example of thermal fluctuations



Holt et. al. (PRL 83, 3317)
X-ray data for Si(III)

→ These spots are
→ Bragg peaks
($\delta(\vec{q} - \vec{G})$ terms)

→ These correspond to
→ thermal diffuse scattering

U(q) part (theory)

| Probes | Light | X-ray | Neutron | Electron |
|---------------------|---------------------------|---------------------------|--------------|-----------------|
| Interaction | Relatively weak | Weak | Very weak | Strong |
| Primary Interaction | Charge | Charge | Spin Nucleus | Charge |
| Other interactions | Spin (SO) | Spin (SO) | | Spin (Exchange) |
| Probing depth | Medium (~ μm) | Medium (~ μm) | Long (~cm) | Short (~nm) |
| Index of refraction | 1-2 | $N \sim 1 - \delta$ | | |
| Multiple scattering | Y | N | N | Y |
| | | | | |
| | | | | |
| | | | | |

U(q) part (expt)

| Probes | Light | X-ray | Neutron | Electron |
|------------------------|---------------------------------|----------------------------|---------------------------|-----------------------------|
| Wavelength | 500nm | $\sim 1 \text{ \AA}$ | $\sim 1 \text{ \AA}$ | $0.01 \sim 0.1 \text{ \AA}$ |
| $Q(2\pi/\lambda)$ | $\sim 10^{-3} \text{ \AA}^{-1}$ | $\sim 6 \text{ \AA}^{-1}$ | $\sim 6 \text{ \AA}^{-1}$ | $\sim 60 \text{ \AA}^{-1}$ |
| Diffraction | n/a | Y | Y | Y |
| Scattering | Y | Y | Y | N |
| Energy | 1-2 eV | $\sim 10 \text{ keV}$ | $\sim 30 \text{ meV}$ | 1-100 keV |
| Spectroscopy | Very good | OK (IXS) | Very good | OK (EELS) |
| Source | Bright (laser) | Bright (synchrotron, XFEL) | Dim | Does not matter |
| Focusing (sample size) | Good | Good | Bad | Good |
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